Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination CHEN ET AL.	
09/843,358		
Examiner	Art Unit	
Nhan T. Le	2618	

Date	Examiner W, Le
15/12/06	N.Le
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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